

SHEET 1 OF 1

LIST C	OF ART CITE	ATTY. DOCKET NO. LT-0034	APPLN. SERIAL NO. 10/743,303									
2.07		APPLICANT(S)  Cheul Kyung HAN										
	(PTO-1	FILING DATE December 23, 2003		GROUP 2627								
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EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME		CLASS	SUBCLASS	FILING DATE					
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/JH/	JP 2001-067669	03/16/2001	Japan (Japanese Full Text and English Abstract)				Х					
/JH/	CN 1276597	12/13/2000	China (Chinese Full Text and English Abstract)				X					
/JH/	EP 1 174 862	06/19/2001	Europe			<u> </u>	X					
/JH/	EP 1 211 678	11/29/2001	Europe				X					
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	Korean Office Act				Service Company Control							
	Chinese Office Action dated July 22, 2005 and its English translation.											
	European Search	ceport dated F	enalsty 2n 20	7.								
	European Search Report dated February 26, 2007.											
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY		CLASS	SUBCLASS	Translation Yes No
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